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Atty. Dkt. No. 064192-0107

***IN THE UNITED STATES PATENT AND TRADEMARK OFFICE***

Applicant: Matthias SLODOWSKI  
Title: APPARATUS AND METHOD FOR THIN-LAYER  
METROLOGY  
Appl. No.: 10/777,162  
Filing Date: 02/13/2004  
Examiner: Gordon J. Stock, Jr.  
Art Unit: 2877  
Confirmation No.: 5100

**AMENDMENT AND REPLY UNDER 37 CFR 1.111**

Mail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

This communication is responsive to the Non-Final Office Action dated December 19, 2006, concerning the above-referenced patent application.

**Amendments to the Claims** are reflected in the listing of claims which begins on page 2 of this document.

**Remarks/Arguments** begin on page 6 of this document.